Jayesh D Chauhan
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Education Qualification

BVM Engineering, Vallabh Vidyanagar, Sardar Patel University
Bachelor of Engineering: Electronics Engg., First class,1994

G H Patel College of Engineering & Technology, V V Nagar, Sardar Patel University
Master of Engineering: Communication Engg., first class with Distinction, 2009
Thesis: Robust M Estimation For Machine Vision Applications
Guided By: Dr. Chintan K. Modi, Ex. HOD, EC Dept. GCET, V V Nagar

Annamali University, Directorate of Distance Education
Post Graduate : Value Education & Spirituality **,** first class with Distinction, 2010
Title of Field Project: Study on People Attitude Towards Health

Annamali University, Directorate of Distance Education
M.Sc (Lateral Entry): Value Education & Spirituality **,** first class with Distinction, 2011
Title of Field Project: Health Awareness amongst Diploma Engineering Students
                                    (Of Final Year Students in BBIT, V V Nagar)

Teaching Experience

B & B Inst. Of Technology, V V Nagar   24Yrs (01-12-1999 to Present
Teaching Subjects:

	Microprocessor & Assembly Language Programming, Electronics Instrument & Measurement, VLSI Technology, Microcontroller & Embedded System, Electronics Project, Antenna & Wave Propagation, Digital Logic Design.
Subjects of Interest:	Image Processing, VLSI, ASIC, Signal Processing, Embedded System, Machine Vision
Soft Skills:	Life Skill Development, Mind Power

Industrial Experience	
GCEL, Gandhinagar	**05 Year**
Service engineer	**1994 To 1999**

Publication Details

International Journal Papers:

1. **Jayesh D Chauhan**, Chintan K Modi and Kunal J. Pithadiya, "Selecting most favorable rho function for robust M estimator for surface roughness estimation using machine vision", International Journal of Advanced Manufacturing Systems (IJAMS) Vol-1, No 1, **2010,** pp-67-74, International Science Press.
2. Kunal J. Pithadiya, Chintan K Modi and **Jayesh D Chauhan,** "Selecting the Most Favourable Edge Detection Technique for Liquid Level Inspection in Bottles", International Journal of Computer Information Systems and Industrial Management Applications. (IJCISIM), ISSN: 2150-7988 Volume 3, **2011**, pp: 34-44, http://www.miralabs.org/ijcisim.
3. Dr. Chintan K. Modi, **Jayesh D. Chauhan**, and Kunal J. Pithadiya, "Selecting Most Favorable Robust Estimator for Surface Roughness Estimation Using Machine Vision", Journal of Manufacturing Technology Research (JMTR), ISSN: 1943-8095, Nova Publisher, Vol, 3, Issue: 3-4, **2012** https://www.novapublishers.com.

International Conference Papers:

1. **Jayesh D. Chauhan**, Chintan K. Modi, Kunal J. Pithadiya, "Comparison of Redescending and Monotone M Estimator for Surface Roughness Estimation Using Machine Vision", Proceedings of the International Conference on Emerging Trends in Engineering & Technology 2009 **(ICTET-09), pp. 464-469**, IEEE Computer Society Washington, DC, USA ©2009, ACM Digital Library , ISBN: 978-0-7695-3884-6.
2. Kunal J. Pithadiya**,** Chintan K. Modi, **Jayesh D. Chauhan**, "Comparison of Optimal Edge Detection Algorithms for Liquid Level Inspection in Bottles", Proceedings of the International Conference on Emerging Trends in Engineering & Technology **(ICTET-09**), **pp. 447-452**,IEEE Computer Society Washington, DC, USA ©2009, ACM Digital Library , ISBN: 978-0-7695-3884-6.
3. **Jayesh D. Chauhan**, Chintan K. Modi, Kunal J. Pithadiya, "Location M estimator for liquid level inspection using Machine Vision", Proceedings of the International Conference on Signals, Systems and Communication 2009 **(ICSSC-2009)**,pp.228-234, Anna University, Chennai.
4. Kunal J. Pithadiya, Chintan K. Modi, **Jayesh D. Chauhan,** "Quality Inspection of Surface Mount Capacitor Using Optimal Edge detector", Proceedings of the International Conference on Signals, Systems and Communication 2009 (ICSSC-2009),pp.81-86,, Anna University, Chennai.

5. **Jayesh D Chauhan,** Chintan K Modi, Kavindra Jain and Kunal J. Pithadiya, "Robust M Estimator for Surface Roughness Estimation Using Machine Vision", Proceedings of the International Conference on Advances in Mechanical Engineering, **pp-810-814 (ICAME-2009)** 2009, S.V. National Institute of Technology, Surat.

6. **Jayesh D. Chauhan,** Chintan K. Modi, Kunal J. Pithadiya, "Location M estimator with optimal edge detector for quality inspection of surface mount device capacitor", Proceedings of the International Conference and Workshop on Emerging Trends in Technology 2010 **(ICWET '10),pp- 595-600**,ACM Digital Library 2010, ISBN 978-1-60558-812-4.

7. Kunal J. Pithadiya, Chintan K. Modi, **Jayesh D. Chauhan**, "Machine vision based liquid level inspection system using ISEF edge detection technique", Proceedings of the International Conference and Workshop on Emerging Trends in Technology 2010 **(ICWET '10),pp- 601-605**,ACM Digital Library 2010, ISBN 978-1-60558-812-4.

National Conference Paper:

1. Kunal J. Pithadiya, Chintan K. Modi, **J. D. Chauhan,** Kavindra Jain, "Performance Evaluation of ISEF and Canny Edge detector in Acrylic fiber quality controlproduction", National Conference on "Innovations in Mechatronics Engineering 2009" (IME-09) ,GCET, V V Nagar.

Academic and Co-Curricular Activities

- Life Member of ISTE (LM-28640)
- Worked as a GTU Zonal Officer at Zone-3, Vallabh Vidyanagar
- Worked Syllabus Revision committee member, CDC (GTU) , Ahmedabad
- Worked as a Committee member, EC department, NBA Accreditation
- Worked as a Project Guide for the Project Exhibition (CREATO) at BBIT, V V Nagar
- Worked as a Co-coordinator of STTP based on "Multisim" ,EC department, BBIT
- Worked as a III cell member, EC department, BBIT
- Worked as a Student Central committee member, BBIT
- Worked as a committee member, Annual day celebration, BBIT

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